Masters of Science Presentation (Exam)

Date: Friday, November 6, at 9:00 am, Catherine Berrouet will present:

Title: Labeled Point Pattern Matching by Delaunay Triangulation and Maximal Cliques (by Hideo Ogawa)

Abstract: In many problems of pattern recognition, objects in an image may be efficiently represented by a set of labeled points. Ogawa's paper

describes a method for matching labeled point patterns where the Delaunay triangulation is used to partition a point pattern into a set of triangles,

and the largest maximal clique of the consistency graph for each triangle is used to obtain the largest set of mutually consistent point pairs. Since

this proposed method is invariant under affine transformation of point patterns and allows for additions and deletions of points and some random

perturbations in the irrelative locations, I include an implementation of Ogawa's method towards a fingerprint authentication algorithm which

detects matched fingerprint pairs by finding mutually consistent point pairs.

Meeting information:

Join Zoom Meeting

https://fau-edu.zoom.us/j/81672738144?pwd=R1RqbkZBOVFVZ1V1TkdLaU5mbEF3dz09